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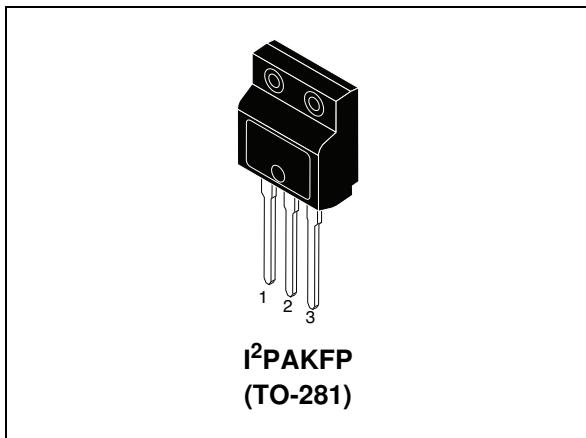
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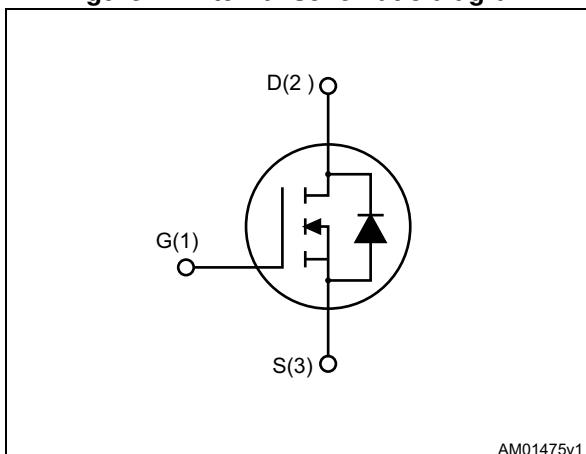
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## N-channel 600 V, 0.168 Ω typ., 17 A MDmesh™ II Power MOSFET in a I<sup>2</sup>PAKFP package

Datasheet – production data



**Figure 1. Internal schematic diagram**



## Features

Order codes	V <sub>DS</sub> @T <sub>jmax</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STFI24NM60N	650 V	0.19 Ω	17 A

- Fully insulated and low profile package with increased creepage path from pin to heatsink plate
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

## Applications

- Switching applications

## Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary**

Order code	Marking	Packages	Packaging
STFI24NM60N	24NM60N	I <sup>2</sup> PAKFP (TO-281)	Tube

## Contents

<b>1</b>	<b>Electrical ratings</b>	<b>3</b>
<b>2</b>	<b>Electrical characteristics</b>	<b>4</b>
2.1	Electrical characteristics (curves)	6
<b>3</b>	<b>Test circuits</b>	<b>8</b>
<b>4</b>	<b>Package mechanical data</b>	<b>9</b>
<b>5</b>	<b>Revision history</b>	<b>11</b>

# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate- source voltage	$\pm 30$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	17 <sup>(1)</sup>	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	11 <sup>(1)</sup>	A
$I_{DM}^{(2)}$	Drain current (pulsed)	68 <sup>(1)</sup>	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	30	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	15	V/ns
$V_{ISO}$	Insulation withstand voltage (RMS) from all three leads to external heat sink ( $t=1\text{ s}; T_C=25^\circ\text{C}$ )	2500	V
$T_J$ $T_{stg}$	Operating junction temperature Storage temperature	-55 to 150	$^\circ\text{C}$

1. Limited by maximum junction temperature.
2. Pulse width limited by safe operating area.
3.  $I_{SD} \leq 17\text{ A}$ ,  $di/dt \leq 400\text{ A}/\mu\text{s}$ , peak  $V_{DS} \leq V_{(\text{BR})DSS}$ ,  $V_{DD} = 80\% V_{(\text{BR})DSS}$

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max.	4.17	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max.	62.5	$^\circ\text{C}/\text{W}$

**Table 4. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or non-repetitive (pulse width limited by $T_J$ max)	6	A
$E_{AS}$	Single pulse avalanche energy (starting $T_J = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ )	300	mJ

## 2 Electrical characteristics

( $T_{case} = 25^\circ C$  unless otherwise specified)

**Table 5. On /off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0, I_D = 1 \text{ mA}$	600			V
$I_{DSS}$	Zero gate voltage drain current	$V_{GS} = 0, V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0, V_{DS} = 600 \text{ V}, T_C = 125^\circ C$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0, V_{GS} = \pm 25 \text{ V}$			$\pm 100$	nA
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(on)}$	Static drain-source on- resistance	$V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$		0.168	0.19	$\Omega$

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 50 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0$	-	1330	-	pF
$C_{oss}$	Output capacitance		-	80	-	pF
$C_{rss}$	Reverse transfer capacitance		-	3.2	-	pF
$C_{oss eq.}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0$	-	182	-	pF
$R_g$	Gate input resistance	$f=1 \text{ MHz open drain}$	-	5	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 17 \text{ A}, V_{GS} = 10 \text{ V}$ <i>(see Figure 15)</i>	-	44	-	nC
$Q_{gs}$	Gate-source charge		-	7	-	nC
$Q_{gd}$	Gate-drain charge		-	24	-	nC

1.  $C_{o(\text{eff})}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DS}$ .

**Table 7. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 8.5 \text{ A}, R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ <i>(see Figure 14)</i>	-	11.5	-	ns
$t_{r(v)}$	Voltage rise time		-	16.5	-	ns
$t_{d(off)}$	Turn-off-delay time		-	73	-	ns
$t_{f(i)}$	Fall time		-	37	-	ns

**Table 8. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max	Unit
$I_{SD}$	Source-drain current		-		17	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		68	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 17 \text{ A}, V_{GS} = 0$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 17 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ <i>(see Figure 16)</i>	-	340		ns
$Q_{rr}$	Reverse recovery charge		-	4.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	27		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 17 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 60 \text{ V}$ $T_J = 150^\circ\text{C}$ <i>(see Figure 16)</i>	-	404		ns
$Q_{rr}$	Reverse recovery charge		-	5.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	28		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

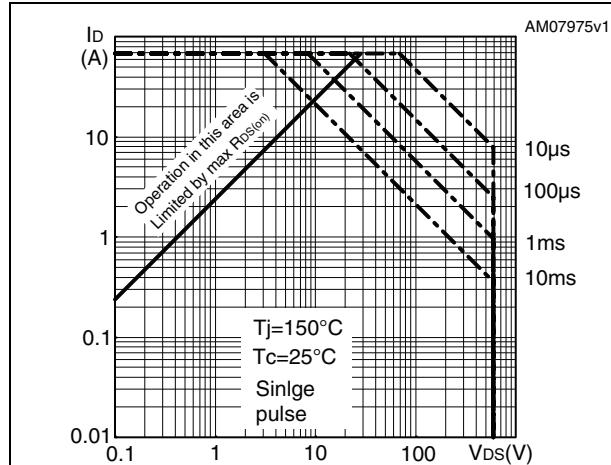


Figure 3. Thermal impedance

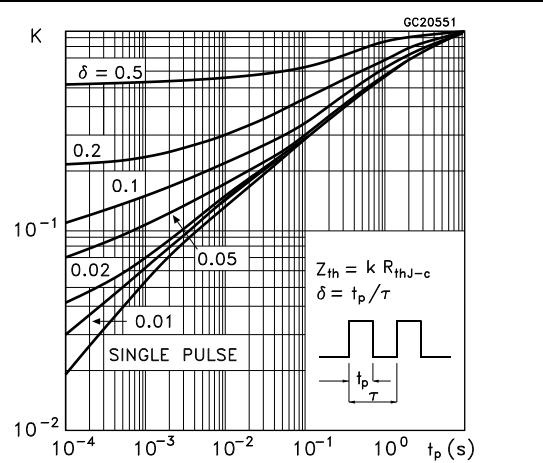


Figure 4. Output characteristics

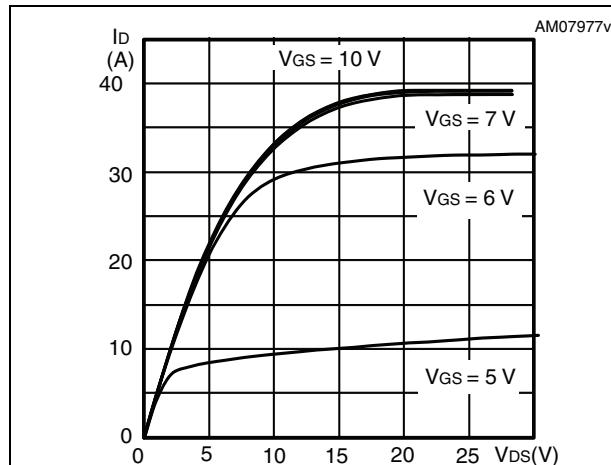


Figure 5. Transfer characteristics

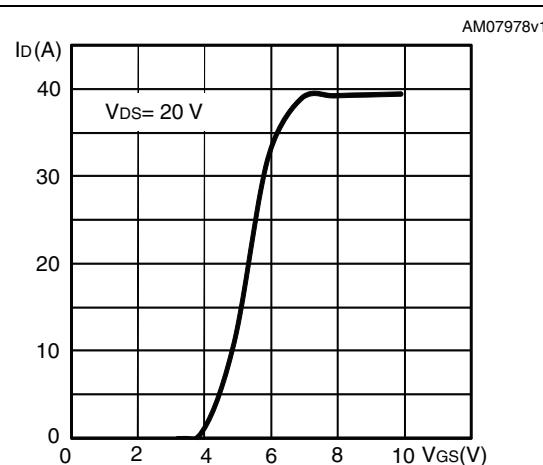


Figure 6. Gate charge vs gate-source voltage

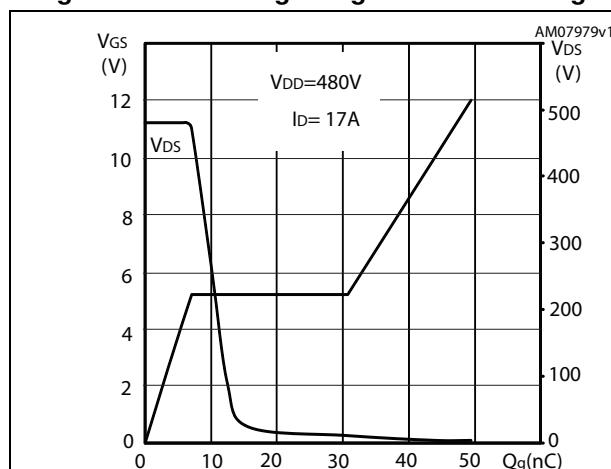
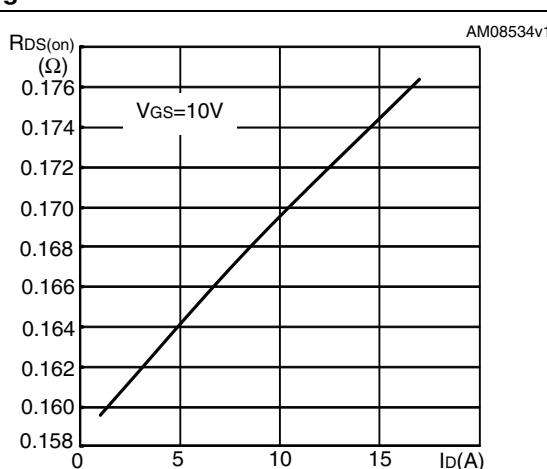
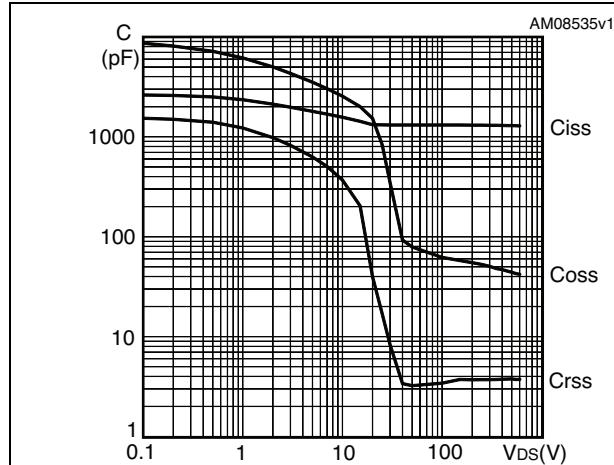
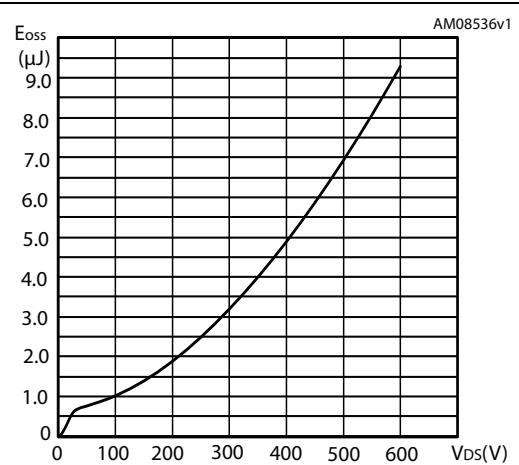
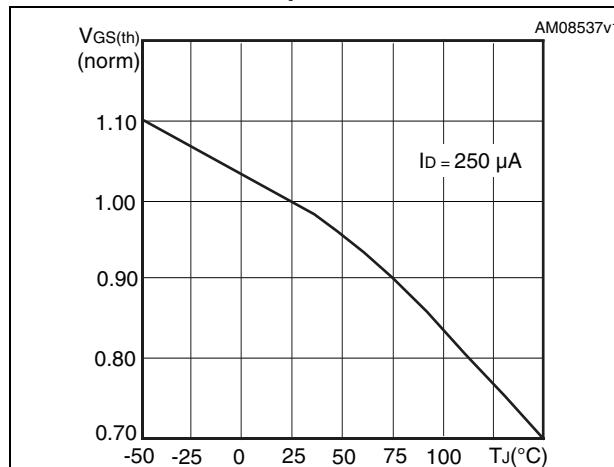
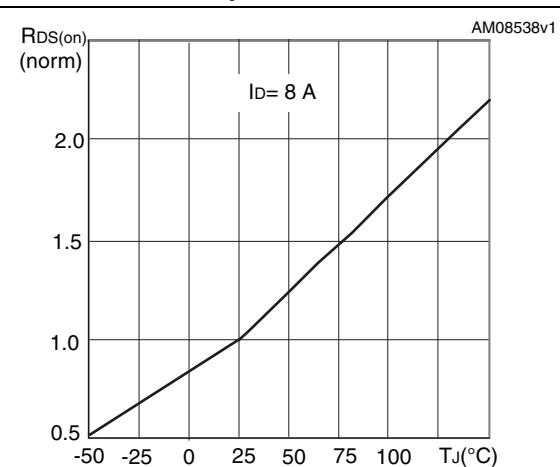
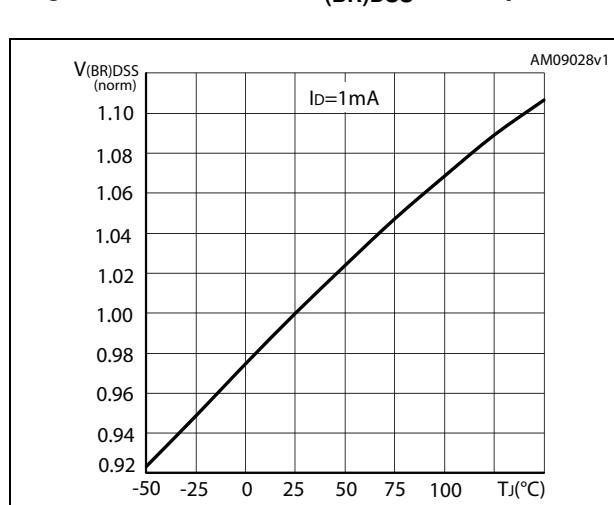
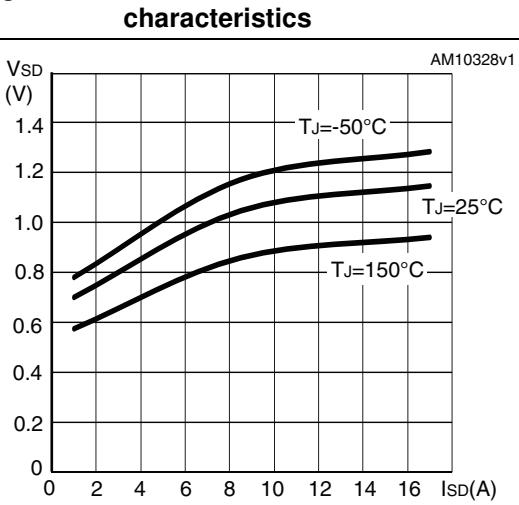


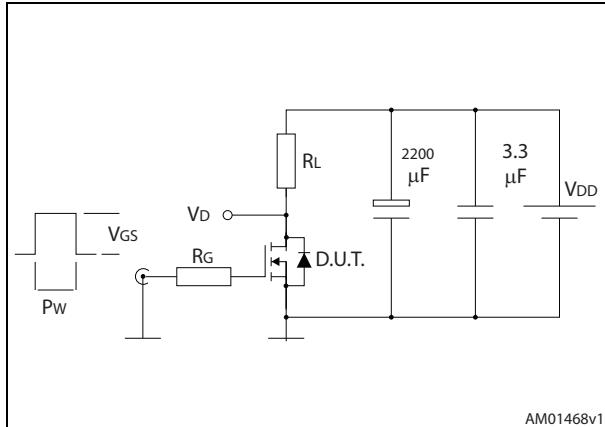
Figure 7. Static drain-source on-resistance



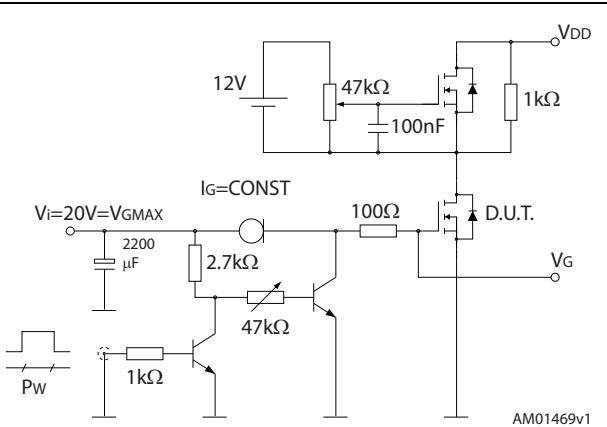
**Figure 8. Capacitance variations****Figure 9. Output capacitance stored energy****Figure 10. Normalized gate threshold voltage vs temperature****Figure 11. Normalized on-resistance vs temperature****Figure 12. Normalized  $V_{(BR)DSS}$  vs temperature****Figure 13. Source-drain diode forward characteristics**

### 3 Test circuits

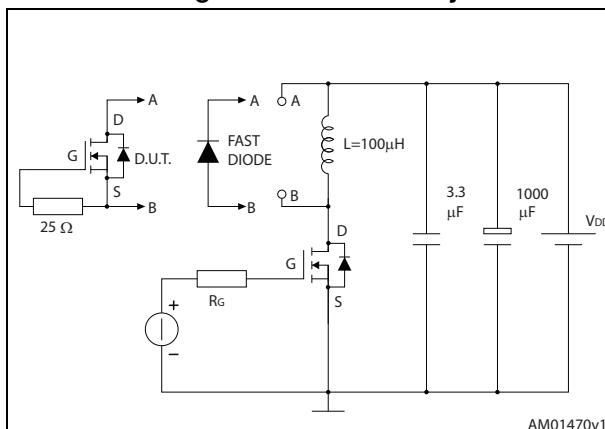
**Figure 14. Switching times test circuit for resistive load**



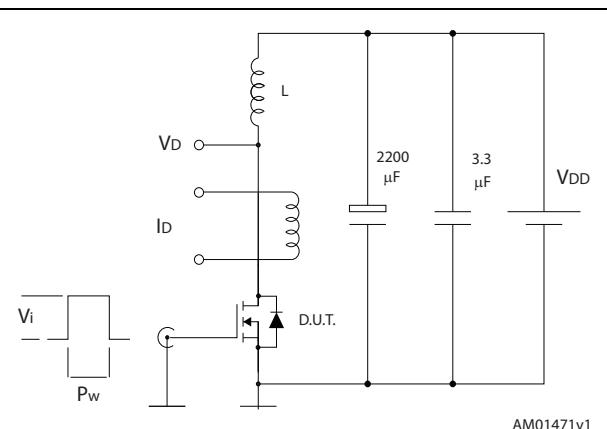
**Figure 15. Gate charge test circuit**



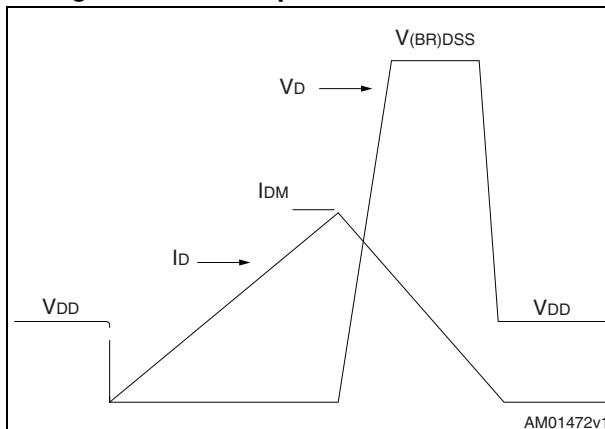
**Figure 16. Test circuit for inductive load switching and diode recovery times**



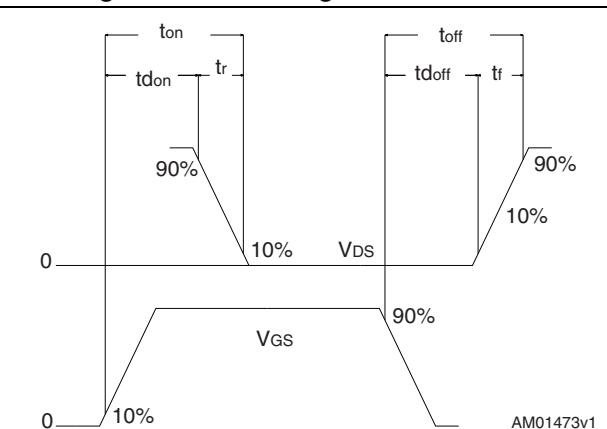
**Figure 17. Unclamped inductive load test circuit**



**Figure 18. Unclamped inductive waveform**

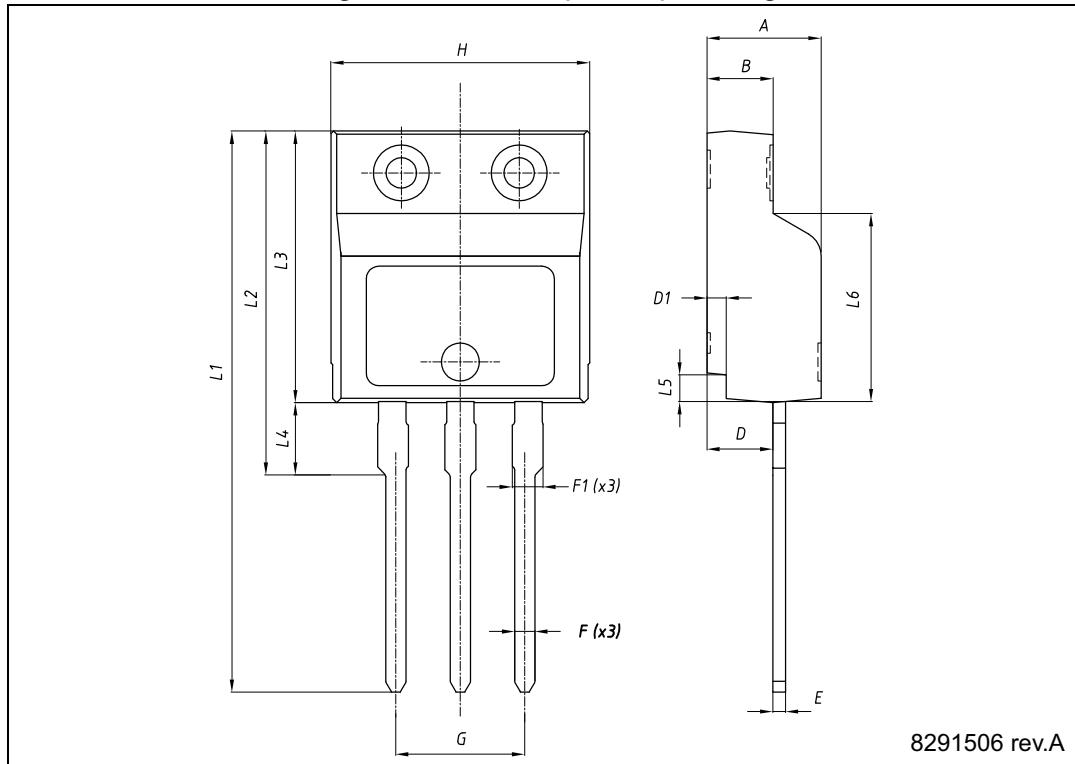


**Figure 19. Switching time waveform**



## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

Figure 20. I<sup>2</sup>PAKFP (TO-281) drawingTable 9. I<sup>2</sup>PAKFP (TO-281) mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	4.40		4.60
B	2.50		2.70
D	2.50		2.75
D1	0.65		0.85
E	0.45		0.70
F	0.75		1.00
F1			1.20
G	4.95	-	5.20
H	10.00		10.40
L1	21.00		23.00
L2	13.20		14.10
L3	10.55		10.85
L4	2.70		3.20
L5	0.85		1.25
L6	7.30		7.50

## 5 Revision history

**Table 10. Document revision history**

Date	Revision	Changes
07-Nov-2011	1	First release.
20-Mar-2012	2	<ul style="list-style-type: none"><li>– Document status promoted from preliminary data to production data.</li><li>– Package name has been updated.</li><li>– Minor text changes.</li></ul>
24-Jul-2014	3	<ul style="list-style-type: none"><li>– Modified: the entire typical values in <a href="#">Table 6</a></li><li>– Minor text changes</li></ul>

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